

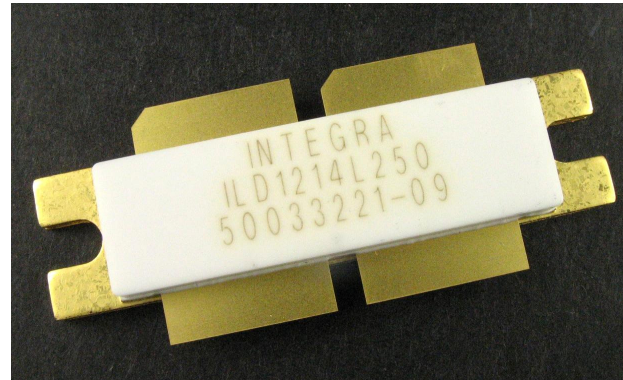
# Part Number: ILD1214L250



**TECHNOLOGIES, INC.**

## L-Band RF Power LDMOS Transistor

The high power pulsed transistor part number ILD1214L250 is designed for L-Band systems operating at 1.2–1.4 GHz. Operating at a pulse width of 1ms with a duty factor of 10%, this dual MOSFET device supplies a minimum of 250 watts of peak pulse power across the instantaneous operating bandwidth of 1.215–1.400 GHz. Fabricated with all gold metal contact, wire bonding and package for maximum reliability. All devices are 100% screened for large signal RF parameters in the broadband RF test fixture across the entire specified operating bandwidth with no variable or external tuning.



### Silicon LDMOS

- High Power Gain
- Superior thermal stability

### Class AB Operation

- Gate biased to  $I_{DQ}=2 \times 250 \text{mA}$

### Configuration

- Common Source

### Gold Metal

- Gold Chip Metal
- Gold Wire Bond
- Maximum Reliability

### Package

- Thermally Enhanced
- Gold Metal based

### Epoxy Sealed Lid

- Gross Leak Qualified

### RF Test Fixture

- Broadband
- Matched to 50Ω
- Long-term Correlation
- 100% Device RF Screening
- No External Tuning required

## TYPICAL DATA TYPICAL DATA TYPICAL DATA TYPICAL DATA

Device	Bias (A)	Freq (MHz)	PW (ms)	Duty (%)	V <sub>DD</sub> (V)	P <sub>IN</sub> (W)	IRL (dB)	P <sub>OUT</sub> (W)	G <sub>p</sub> (dB)	I <sub>d</sub> (A)	η <sub>D</sub> (%)
D4445-3	0.5	1400	1	10	30.0	17.4	-19	250	11.6	13.80	60
		1400	1	10	30.0	12.0	-20	200	12.2	11.40	58
		1400	1	10	30.0	7.0	-20	120	12.3	7.48	53
		1300	1	10	30.0	14.1	-20	250	12.5	14.40	58
		1300	1	10	30.0	11.0	-20	200	12.6	12.40	54
		1300	1	10	30.0	6.9	-20	120	12.4	8.60	47
		1215	1	10	30.0	11.3	-20	250	13.5	13.20	63
		1215	1	10	30.0	8.4	-20	200	13.7	10.80	62
		1215	1	10	30.0	5.2	-20	120	13.7	7.14	56

**MAXIMUM RATINGS**

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
BD	Drain-Source Voltage	$V_{DS}$	--	65	V	--
BD	Gate-Source Voltage	$V_{GS}$	-0.5	+12	V	--
BD	Storage Temperature Range	$T_{STG}$	-40	+150	°C	--
BD	Operating Junction Temperature Range	$T_J$	-55	+200	°C	--
Note	Screen 'BD' = parameter qualified By Design.					

**THERMAL CHARACTERISTICS**

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
BD	Thermal Resistance	$R_{TH(JC)}$	--	0.15	°C/W	$V_{dd}=30V, I_{DQ}=2x250mA, T_F=70\pm5^\circ C, P_{OUT}=250W$
Note	Screen 'BD' = parameter qualified By Design.					

**PROCESSING SPECIFICATIONS**

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
100%	DC Wafer Probe	--	--	--	--	Per Integra specification.
Q1	Wafer DC and RF Qualification	--	--	--	--	Per Integra specification.
LM	Wire Bond Strength	--	--	--	--	Line monitor per Integra specification.
100%	Pre-cap visual inspection	--	--	--	--	Per Integra specification
100%	Gross leak test	--	--	--	--	MIL-STD-750D, Method 1071, Test Condition C
Note	Screen 'Q1' = parameter is qualified by assembly and test of 3 pieces minimum per wafer.					
Note	Screen 'LM' = parameter is qualified by assembly line monitor.					

**DC ELECTRICAL CHARACTERISTICS**

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
100%	Drain-Source Breakdown Voltage (each side)	$BV_{DSS}$	65	--	V	$I_D = 40mA, V_{GS} = 0V, T_F = 25\pm5^\circ C$
100%	Drain Leakage Current (each side)	$I_{DSS}$	--	10	$\mu A$	$V_{DS} = 28V, V_{GS} = 0V, T_F = 25\pm5^\circ C$
100%	Gate Threshold Voltage (each side)	$V_{GS}$	1.5	2.5	V	$I_D = 100mA, V_{DS} = 5V, T_F = 25\pm5^\circ C$
100%	Gate Leakage Current (each side)	$I_{GSS}$	--	1.0	$\mu A$	$V_{GS} = 5V, V_{DS} = 0V, T_F = 25\pm5^\circ C$

**RF ELECTRICAL CHARACTERISTICS**

Screen	Parameter	Symbol	Min	Max	Units	Test Conditions
100%	Input Return Loss	IRL	-18	-7	dB	$V_{DD}=V1; I_{DQ}=I_{DQ1}; T_F=T_{F1}; P_O=P_{OUT1}; F=F1, F2, F3; PW1, DF1$
100%	Input Power	$P_{in}$	5.60	25.00	W	$V_{DD}=V1; I_{DQ}=I_{DQ1}; T_F=T_{F1}; F=F1, F2, F3; PW1, DF1$
100%	Power Gain	$G_P$	10	16.5	dB	$V_{DD}=V1; I_{DQ}=I_{DQ1}; T_F=T_{F1}; P_O=P_{OUT1}; F=F1, F2, F3; PW1, DF1$
100%	Pulse Amplitude Droop	Drp	-0.5	0.5	dB	$V_{DD}=V1; I_{DQ}=I_{DQ1}; T_F=T_{F1}; P_O=P_{OUT1}; F=F1, F2, F3; PW1, DF1$
100%	Gain Flatness versus Frequency	dG	0	2.5	dB	$V_{DD}=V1; I_{DQ}=I_{DQ1}; T_F=T_{F1}; P_O=P_{OUT1}; F=F1, F2, F3; PW1, DF1$
100%	Drain Efficiency	Nd'	40	75	%	$V_{DD}=V1; I_{DQ}=I_{DQ1}; T_F=T_{F1}; P_O=P_{OUT1}; F=F1, F2, F3; PW1, DF1$
100%	Stability into 2:1 VSWR	VSWR-S	S	--	--	$V_{DD}=V1; I_{DQ}=I_{DQ1}; T_F=T_{F1}; P_O=P_{OUT1}; F=F1, F2, F3; PW1, DF1$ Rotate 2:1 output VSWR through 360° phase. No oscillatory or pulse break-up characteristics allowed on detected output pulse.
100%	3:1 Load Mismatch Tolerance	LMT	P	--	--	$V_{DD}=V1; I_{DQ}=I_{DQ1}; T_F=T_{F1}; P_O=P_{OUT1}; F=F1, F2, F3; PW1, DF1$ Rotate 3:1 output VSWR through 360° phase. Post test $P_O =$ Pre test $P_O \pm 10W$ .
Note	$V1=30V; I_{DQ1}$ (Drain Quiescent Current)=250mA/side PW1(Pulse Width 1) =1ms; DF1(Duty Factor 1)=10%; $P_{OUT1}=250W; F1=1.215GHz, F2=1.300GHz, F3=1.400GHz$ $T_{F1}$ (Flange Temp)=25±5°C RF Electrical characteristics tested in broadband RF test fixture					

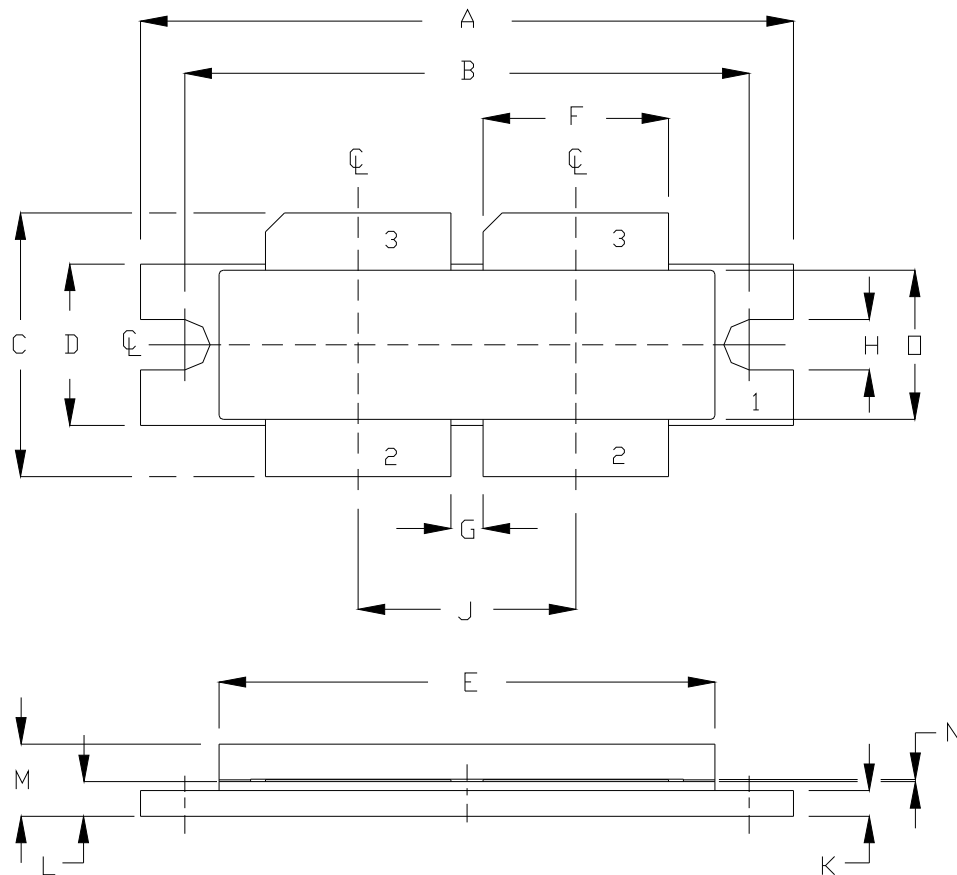
**BROADBAND RF TEST FIXTURE IMPEDANCE CHARACTERISTICS**

Frequency (GHz)	$Z_{IF}$ ( $\Omega$ )	$Z_{OF}$ ( $\Omega$ )
1.215	1.8 -j1.2	1.2 -j2.9
1.300	1.7 -j0.4	1.2 -j2.1
1.400	1.6 +j0.6	1.2 -j1.4

$Z_{IF}$  = The test fixture input impedance for each side.

$Z_{OF}$ = The test fixture output impedance for each side.

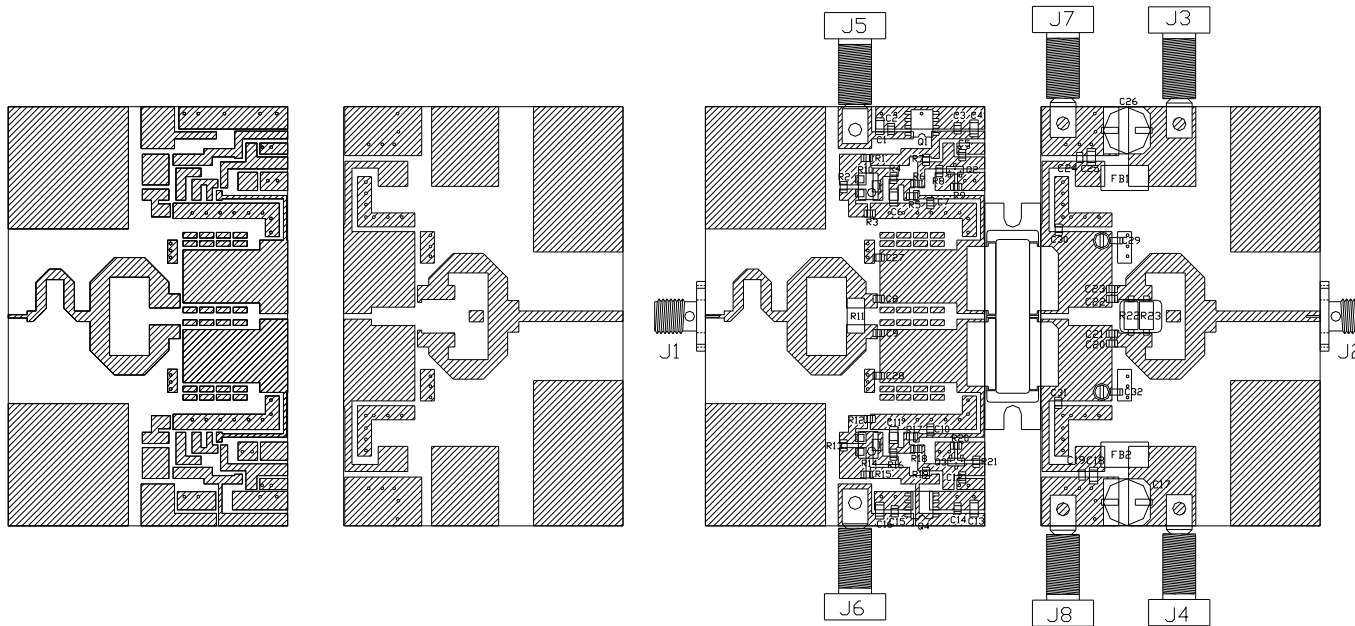
**PACKAGE DIMENSIONAL OUTLINE DRAWING**



DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	1.615	1.625	41.02	41.27
B	1.395	1.405	35.43	35.69
C	0.634	0.674	16.10	17.12
D	0.395	0.405	10.03	10.29
E	1.219	1.241	30.96	31.52
F	0.455	0.465	11.56	11.81
G	0.075	0.085	1.90	2.16
H	0.120	0.130	3.05	3.30
J	0.535	0.545	13.59	13.84
K	0.059	0.069	1.499	1.753
L	0.081	0.091	2.06	2.31
M	0.164	0.194	4.16	4.93
N	0.004	0.007	0.10	0.18
□	0.354	0.364	8.99	9.24

PIN SCHEDULE	
1	SOURCE
2	GATE
3	DRAIN

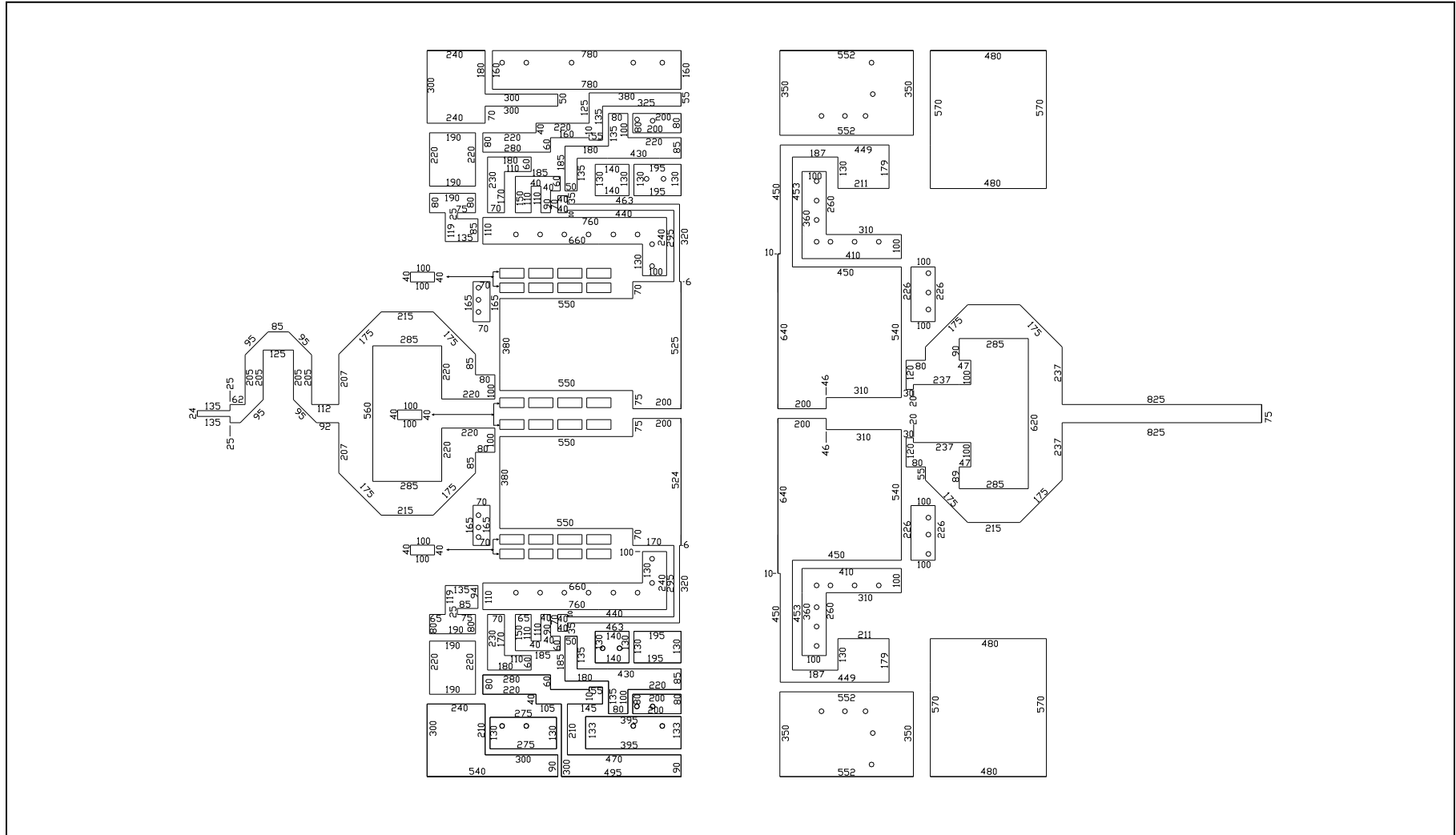
**RF-TEST-FIXTURE ASSEMBLY AND PART LIST**



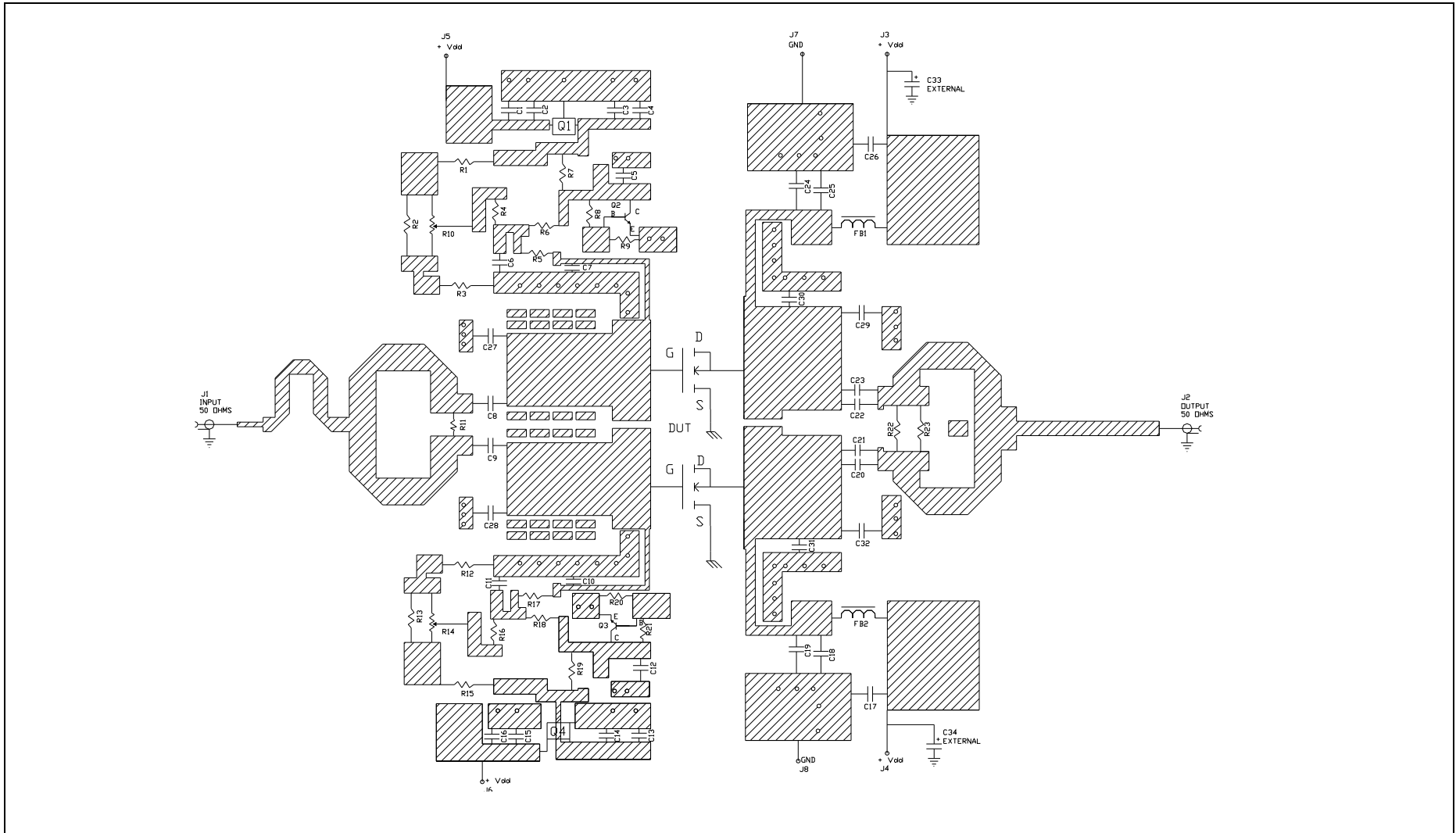
COMPONENT	DESCRIPTION
DUT	TRANSISTOR DUT MOUNT HARD TO THE RIGHT
PC BOARD	ROGERS WRD 6010, 25mil, 1oz, COPPER
C1, C4, C6, C11, C13, C16, C18, C25	CHIP CAPACITOR 1206, 1uF, MURATA GRM31CR72A105KA01L
C2, C3, C5, C7, C8, C9, C10, C12, C14, C15, C19, C24	CHIP CAPACITOR 100pF, ATC 600F101JW250XT
C17, C26	ELECTROLYTIC CAPACITOR 68uF / 50V, 8x10mm NICHICON UUD1H680MUGS
C20, C21, C22, C23	CHIP CAPACITOR 0505, 47pF, ATC 100A
C27, C28	CHIP CAPACITOR 0805, 3.3pF, ATC 600F3R3BW250
C29, C32	CHIP CAPACITOR 0.4-2.5pF, TRIMMER JHANSSEN #27283
C30	CHIP CAPACITOR 0805, 3pF, ATC 600F3R0CV250
C31	CHIP CAPACITOR 0805, 3pF, ATC 600F2R0CV250
C33, C34 (External)	ELECTROLYTIC CAPACITOR, 4700uF / 50V
FB1, FB2	BEAD, 10A STEWARD #28F0181-1SR-10
R1, R15	RESISTOR 0805, 820ohm
R2, R13	RESISTOR 0805, 390ohm
R3, R12	RESISTOR 0805, 150ohm
R4, R16	RESISTOR 0805, 1.8kohm
R5, R17	RESISTOR 0805, 5.1ohm
R6, R18	RESISTOR 0805, 10kohm
R7, R19	RESISTOR 0805, 1kohm
R8, R21	RESISTOR 0805, 8.2kohm

COMPONENT	DESCRIPTION
R9, R20	RESISTOR 0805, 1.5kohm
R10, R14	RESISTOR P01, 200ohm, BURNS #3224W-1-201E
R11	RESISTOR 20ohm, 1W, 5%, 2512
R22, R23	RESISTOR 50ohm, 30W, 2010 ATC LR12010T0050_JBK
Q1, Q4	IC, VREG, S01CB #UA78L08ACD
Q2, Q3	TRANSISTOR NPN, S01-23, MMBT2222AFSCT-ND
J1, J2	SMA CONNECTOR 03 #2052-5636-02
INPUT PC BOARD CARRIER	3 INCH BRASS-07 RPK
OUTPUT PC BOARD CARRIER	3 INCH BRASS-07 RPK
TRANSISTOR CARRIER	4 INCH COPPER-24 RPK
TRANSISTOR CLAMP	NDRYL CLAMP-18J
ALUMINUM HEATSINK	4 INCH HEATSINK-03
J7, J8	BANANA JACK, BLACK
J3, J4	BANANA JACK, RED
J5, J6	BANANA JACK, BLUE
NOTE	FIXTURE HARDWARE DRAWINGS AVAILABLE ON REQUEST

**RF-TEST-FIXTURE CIRCUIT DIMENSIONS**



**RF-TEST-FIXTURE ELECTRICAL SCHEMATIC**



**DEFINITIONS**

<b>Data Sheet Status</b>	
Proposed Specification	This data sheet contains proposed specifications.
Preliminary Specification	This data sheet contains specifications based on preliminary measurements and data.
Product Specification	This data sheet contains final product specifications.
<b>Maximum Ratings</b>	
Stress above one or more of the maximum ratings may cause permanent damage to the device. These are maximum ratings only. Operation of the device at these or at any other conditions above those given in the characteristics sections of the specification is not implied. Exposure to maximum values for extended periods of time may affect device reliability.	

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